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Application/Control No.	Applicant(s)/Patent under Reexamination	
10/568,683	TANAKA ET AL.	
Examiner	Art Unit	_
Matthew Eggerding	1763	

SEARCHED			
Class	Subclass	Date	Examiner
118	715-33	7/18/2007	MTE
156	345.1-55	7/18/2007	MTE
c23c014	\$	7/18/2007	MTE
· c23c016	\$	7/18/2007	MTE
h01l021	\$	7/18/2007	MTE
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
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SEARCH NOT (INCLUDING SEARCH)
·	DATE	EXMR
Inventor search	7/18/2007	MTE
Text searched in US Pat, US PG PUb,. US OCR, JPO, EPO, and Derwent	7/18/2007	MTE
Backwards and forwards citations	7/18/2007	MTE
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